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	tute for form 1449B/PTO	Complete if Known					
•		Application Number	09/939,149				
INF	ORMATION DISCLOSURE	Filing Date	08/24/2001				
ST	ATEMENT BY APPLICANT	First Named Inventor	Paul Mansky crn n 4 2002 2				
017	AILMENT D. M. LIOAN	Group Art Unit	1754 2856				
	(use as many sheets as necessary)	Examiner Name	David Wagins				
Shoot	1 of 0	Attorney Docket Number	1012 110(2001)				

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Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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NOC		U.S. Application Serial No. 09/420,334 entitled " Graphic Design of Combinatorial Material Libraries" (Lacy, et al.) filed on October 18, 1999	<u>/</u> /
JDW	} }	U.S. Patent Application Serial No. 09/305,830 titled "Synthesizing Combinatorial Libraries of Materials" (Rust, et al.) filed on May 5, 1999	902
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JOW	,	The family of applications for U.S. Application Serial No. 09/227,558 entitled, "Apparatus and Method of Research for Creating and Testing Novel Catalysts, Reactions and Polymers" (Turner et al.) filed January 8, 1999	
DW		U.S. Application Serial No. 09/235,368 entitled "Polymerization Method From the Combinatorial Synthesis and Analysis of Organometallic Compounds and Catalysts" (Weinberg et al.) filed on January 21, 1999	
NAC	/	U.S. Provisional Application Serial No. 60/122,704 entitled "Controlled, Stable Free Radical Emulsion and Water-Based Polymerizations" (Klaerner et al.) filed on March 9, 1999	
DW	•	The family of applications for U.S. Application Serial No. 09/567,598 entitled "Polymer Libraries on a Substrate, Method for Forming Polymer Libraries on a Substrate and Characterization Methods with Same" (Boussie et al.) filed May 10, 2000	
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STATEMENT BY APPLICANT	First Named Inventor	Paul Mansky	अला ही				

First Named Inventor Group Art Unit

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٠.		Application Number	09/939,140
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	STATEMENT BY APPLICANT	First Named Inventor	Paul Mansky
		Group Art Unit	1754
	(use as many sheets as necessary)	Examiner Name	David Walls Ins

Attorney Docket Number

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considered. Include copy of this form with next communication to applicant. ¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter

code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Application Number	09/939,149	OILE					
Filing Date	08/24/2001	<u>e/</u>					
First Named Inventor	Paul Mansky	FFR n					
Group Art Unit	17542856	2002 B					
Examiner Name	David W	Malhs &					
Attorney Docket Number	1012-119(200	NODA/) .08/					

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JDW		5,610,325		Rajagopal et al.,	<u> </u>	03/11/1997	07	<u>'3</u>	5	7.39	4
JDW.		5,626,779		Okada , 🔭		05/06/1997	_21	9_	2	91	4
WOL		5,699,159		Mason ,	<u> </u>	12/16/1997	(A)	26	37	2	1
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MCC		5,756,883		Forbes		05/26/1998	0	7.3	55	205	1
IIDW.		5,764,068		Katz et al.	<u>.</u> A.	06/09/1998	32	<u> </u>	D _D	727	1
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DDM		6,315,923		Devenney et al. M		11/13/2001	252		30	94 K	
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Application Number	09/939,149	N.
Filing Date	08/24/2001	6
First Named Inventor	Paul Manksy 🔪	6
Group Art Unit	175428560	
Examiner Name	David Wad	UNS .
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MQL		5,959,297		Weinberg et al.	/ 09/28/1999	250	2.88
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Application Number	09/939,149	7	ز ـ
Filing Date	08/24/2001		₹,
First Named Inventor	Paul Manksy	<u> </u>	
Group Art Unit	1754 2850		2
Examiner Name	David	Nigains	
Attorney Docket Number	1012-119(2001	-021)	ر

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Attorney Docket Number

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
JDW	}	U.S. Patent Application Serial No. 09/939,404 entitled "High Throughput Mechanical Property and Bulge Testing of Material Libraries," (D. Hajduk et al.) filed on August 24, 2001.	
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JDW	<u> </u>	*The family of applications for U.S. Patent Application Serial No. 09/174,856 titled "Graphic Design of Combinatorial Material Libraries" (Lacy, et al.) filed on October 19, 1998.	
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JOH	\ -	*PCT Application No. PCT/US01/11417 entitled "Automated Process Control And Data Management System And Methods", filed 4/6/2001	

Examiner Signature	David	Wiggins	Date Considered	02/04/03
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		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
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Examiner Signature	David	Wiggins	Date Considered	02/04/03
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